

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/845,454	RANGARAJAN ET AL	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
156	345.13	12/15/2005	ВТ		
156	345.15	12/15/2005	ВТ		
156	345.22	12/15/2005	ВТ		
156	345.24	12/15/2005	вт		
156	345.35	12/15/2005	ВТ		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
156	345.13	12/15/2005	ВТ		
156	345.15	12/15/2005	ВТ		
156	345.22	12/15/2005	вт		
156/345.24 156/345.35		12/15/2005	ВТ		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT database	12/15/2005	ВТ		
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